

# PATENT ABSTRACTS OF JAPAN

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## (54) SEMICONDUCTOR INTEGRATED CIRCUIT TEST DEVICE

(57)Abstract:

**PURPOSE:** To save a time required for adjustment by a method wherein a flexible support plate mounted with probes is fixed to the underside of a rubber plate, a pressing member such as machine screws or a pressure plate is made to bear against a region surrounded with the probes of the support plate to sink the support plate.

**CONSTITUTION:** A flexible support plate 4 mounted with probes 6 is fixed to the underside of a rubber plate 5, pressing members 8 and 9 such as machine screws or pressure plates are made to penetrate the region of the support plate 5 surrounded with the probes 6 so as to enable the probes 6 to be inclined inwards sinking the support plate 4. Therefore, the positional fine adjustment of the probes 6 is carried out by changing the pressing members 8 and 9 in depth, so that it can be collectively executed at a time independent of the number of the probes. By this setup, probes can be lessened in time required for adjustment.

